

Resource Summary Report

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Arizona State University Knowledge Enterprise: EMC X-ray Photoelectron Spectroscopy (XPS) Kratos Axis Supra +

RRID:SCR_028605

Type: Tool

Proper Citation

Arizona State University Knowledge Enterprise: EMC X-ray Photoelectron Spectroscopy (XPS) Kratos Axis Supra + (RRID:SCR_028605)

Resource Information

URL: <https://cores.research.asu.edu/materials/equipment/x-ray-photoelectron-spectroscopy>

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Description: Advanced X-ray Photoelectron Spectrometer (XPS) to determine the chemical composition and bonding states of the very outermost surface of a material (the top 10 nm). XPS depth profiling can be performed to determine elemental composition and chemical bonding information for layers below the surface. Relative atomic concentration percentages can be determined with a sensitivity of 0.1 to 1 atomic % for Li and heavier elements. The analysis is carried out in an ultrahigh vacuum system ($\sim 10^{-9}$ Torr/ 10^{-7} Pa or better). It serves researchers from a variety of fields including materials science and engineering, Electronics and Semiconductors, Energy Storage & Conversion, Catalysis & Petrochemicals and Polymer & Surface Engineering. Features: Large area XPS analysis with high sensitivity and faster acquisition times. Parallel XPS imaging from 10 mm² to 200 mm² with 1 μm ultimate spatial resolution. Pre-defined small spot analysis with the smallest diameter 15 μm. XPS Depth-profiling and Angle-Resolved analysis. Dual monochromatic Al/Ag source with a high-energy resolution (Al K-alpha 1486.6eV & Ag L-alpha 2984.2eV, line width 0.48eV on Ag 3d_{5/2} and 0.408eV on Si 2p_{3/2}). A Minibeam 6 Arn⁺ cluster ion gun for relative depth profiling and sputtering cleaning. Multi-Technique Capability: ultraviolet photoelectron spectroscopy (UPS), ion scattering spectroscopy (ISS), and reflection electron energy loss spectroscopy (REELS).

Synonyms: Kratos AXIS Supra+

Resource Type: instrument resource

Keywords: determine chemical composition, bonding states, material surface,

Availability: Commercially available

Specification URL: https://raw.githubusercontent.com/SciCrunch/RRID-Instruments/refs/heads/main/PDF/SCR_028605.pdf

Resource Name: Arizona State University Knowledge Enterprise: EMC X-ray Photoelectron Spectroscopy (XPS) Kratos Axis Supra +

Resource ID: SCR_028605

Alternate IDs: Model_Number_Kratos_AXIS_Supra+

Record Creation Time: 20260624T044607+0000

Record Last Update: 20260829T183545+0000

Ratings and Alerts

No rating or validation information has been found for Arizona State University Knowledge Enterprise: EMC X-ray Photoelectron Spectroscopy (XPS) Kratos Axis Supra +.

No alerts have been found for Arizona State University Knowledge Enterprise: EMC X-ray Photoelectron Spectroscopy (XPS) Kratos Axis Supra +.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.